

TOSHIBA Insulated Gate Bipolar Transistor Silicon N Channel IGBT

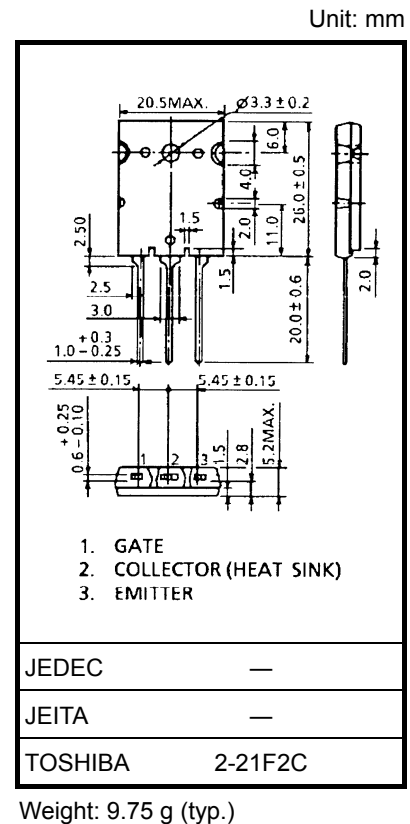
GT60M322

Voltage Resonance Inverter Switching Application
Current Resonance Inverter Switching Application

- Enhancement mode type
- High speed : $t_f = 0.15 \mu s$ (typ.) ($I_C = 60 A$)
- Low saturation voltage : $V_{CE(sat)} = 2.3 V$ (typ.) ($I_C = 60 A$)
- FRD included between emitter and collector
- TO-3P(LH) (Toshiba package name)

Absolute Maximum Ratings ($T_a = 25^\circ C$)

Characteristics		Symbol	Rating	Unit
Collector-emitter voltage		V_{CES}	950	V
Gate-emitter voltage		V_{GES}	± 25	V
Collector current	DC	I_C	60	A
	1ms	I_{CP}	120	
Diode forward current	DC	I_F	25	A
	Pulsed	I_{FP}	50	
Collector power dissipation	@ $T_c = 100^\circ C$	P_C	76	W
	@ $T_c = 25^\circ C$		190	
Junction temperature		T_j	150	$^\circ C$
Storage temperature range		T_{stg}	-55 to 150	$^\circ C$

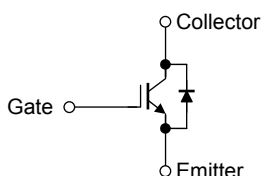


Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

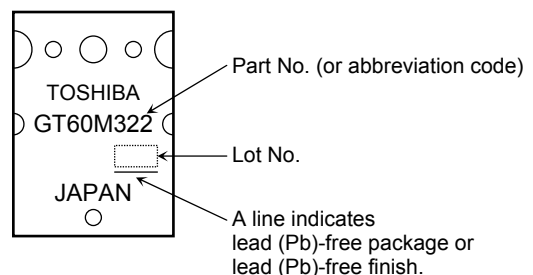
Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance (IGBT)	$R_{th(j-c)}$	0.66	$^\circ C/W$
Thermal resistance (diode)	$R_{th(j-c)}$	1.38	$^\circ C/W$

Equivalent Circuit



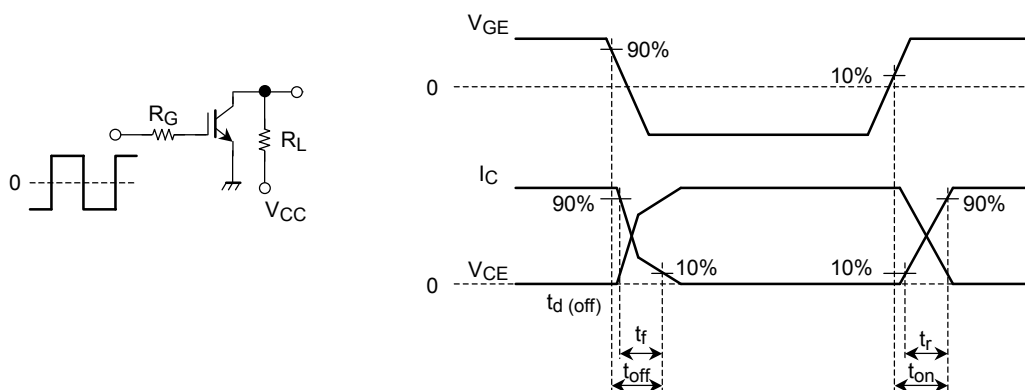
Marking

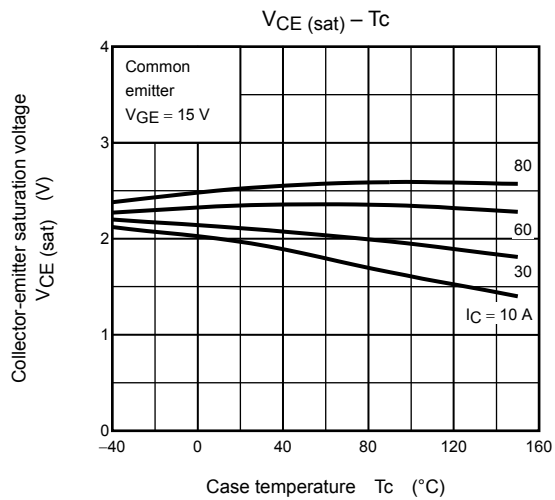
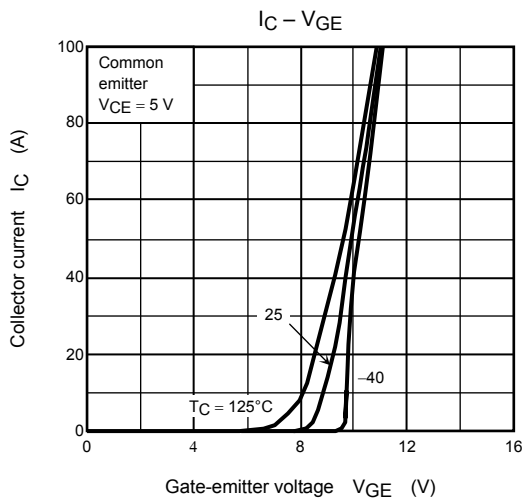
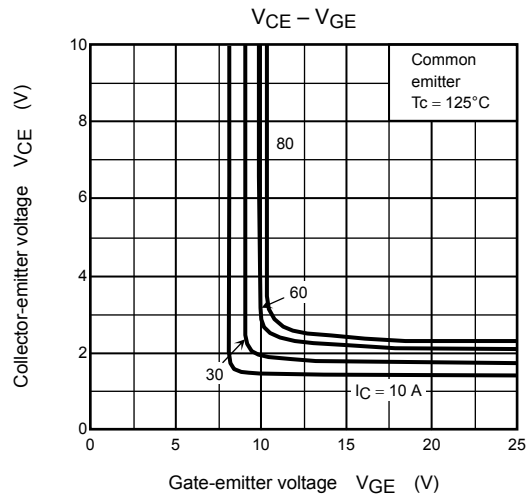
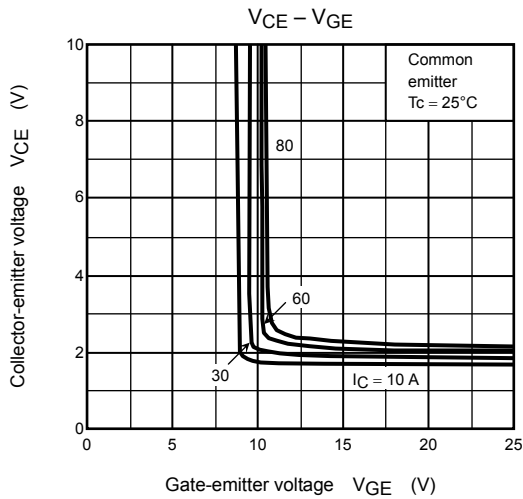
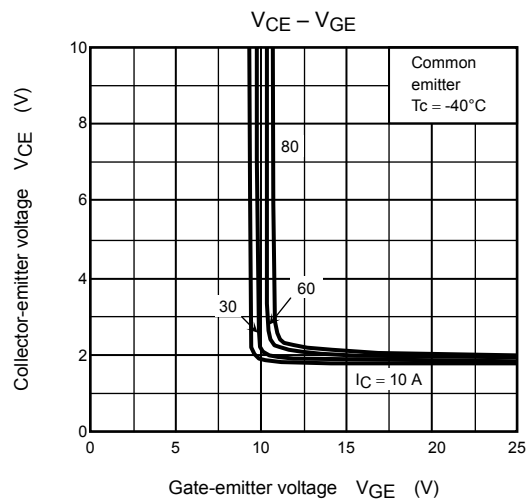
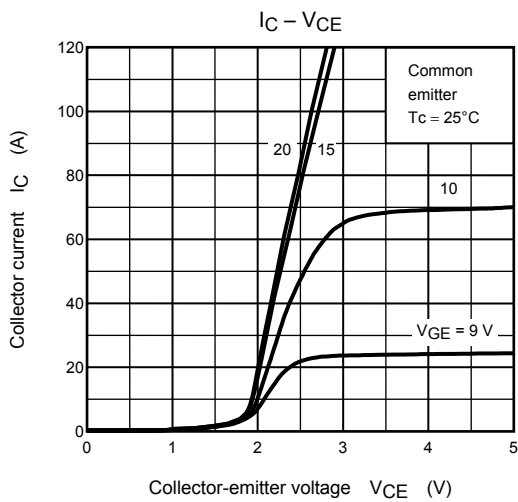


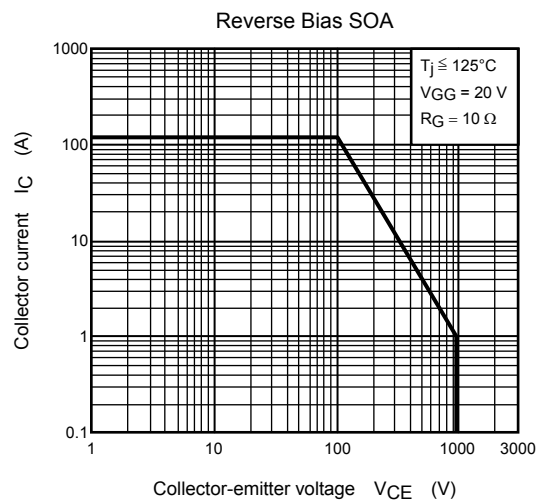
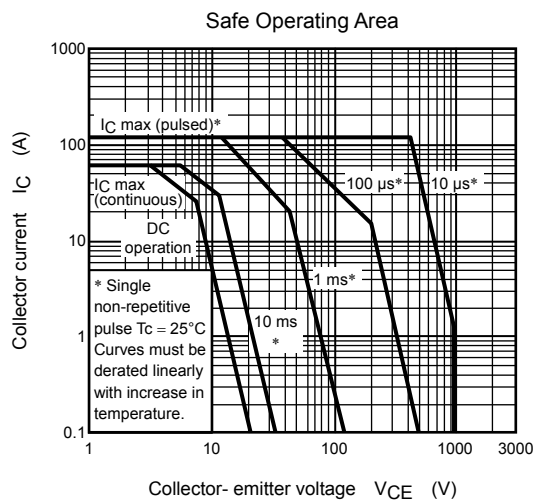
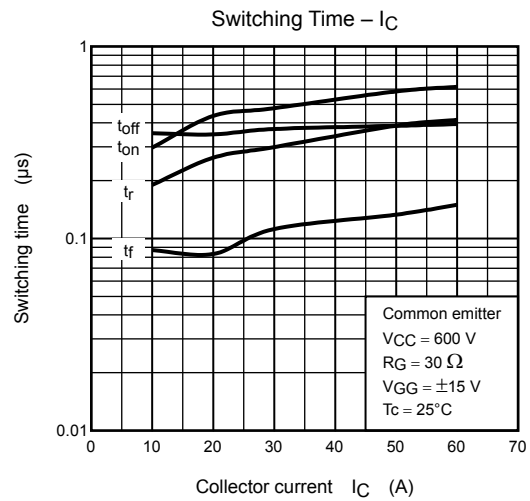
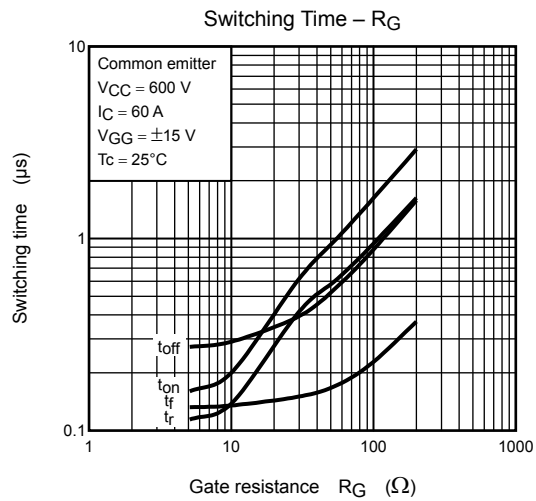
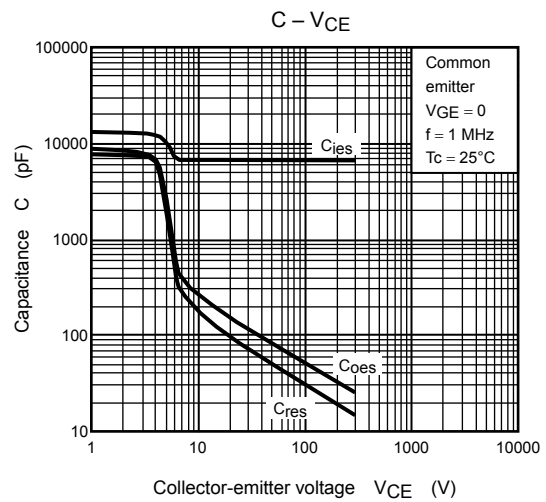
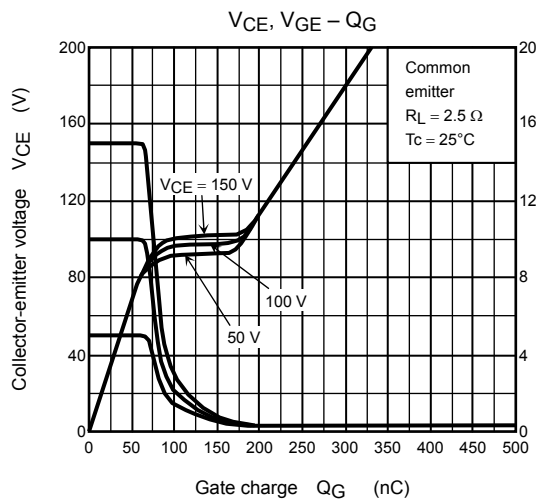
Electrical Characteristics (Ta = 25°C)

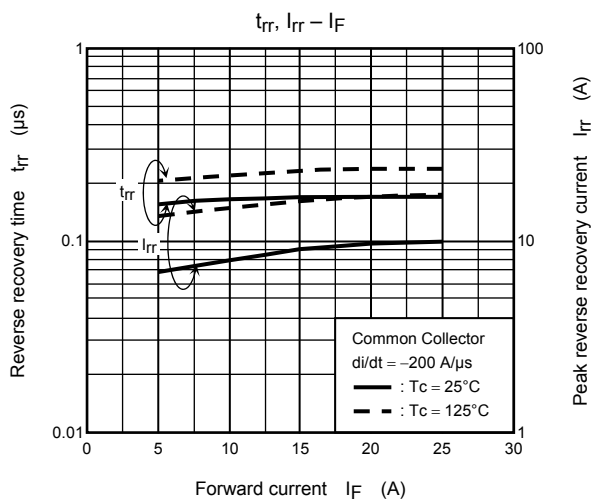
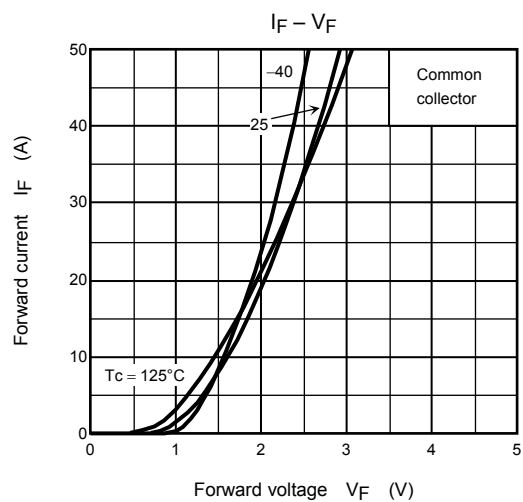
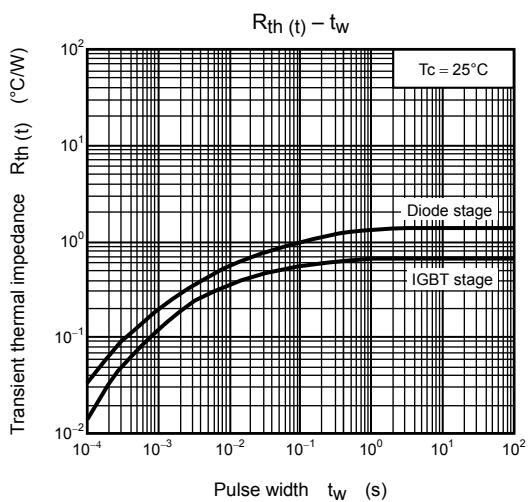
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GES}	$V_{GE} = \pm 25 \text{ V}, V_{CE} = 0$	—	—	± 500	nA
Collector cut-off current		I_{CES}	$V_{CE} = 950 \text{ V}, V_{GE} = 0$	—	—	1.0	mA
Gate-emitter cut-off voltage		$V_{GE}(\text{OFF})$	$I_C = 60 \text{ mA}, V_{CE} = 5 \text{ V}$	6.0	—	9.0	V
Collector-emitter saturation voltage		$V_{CE}(\text{sat})$	$I_C = 60 \text{ A}, V_{GE} = 15 \text{ V}$	—	2.3	2.7	V
Input capacitance		C_{ies}	$V_{CE} = 10 \text{ V}, V_{GE} = 0, f = 1 \text{ MHz}$	—	6800	—	pF
Switching time	Rise time	t_r	Resistive Load $V_{CC} = 600 \text{ V}, I_C = 60 \text{ A}$ $V_{GG} = \pm 15 \text{ V}, R_G = 30 \Omega$ (Note 1)	—	0.42	—	μs
	Turn-on time	t_{on}		—	0.62	—	
	Fall time	t_f		—	0.15	0.21	
	Turn-off time	t_{off}		—	0.39	—	
Diode forward voltage		V_F	$I_F = 25 \text{ A}, V_{GE} = 0$	—	—	3.0	V
Reverse recovery time		t_{rr}	$I_F = 25 \text{ A}, di/dt = -200 \text{ A}/\mu\text{s}$	—	—	0.35	μs

Note 1: Switching time measurement circuit and input/output waveforms









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